Report on GEM Standalone Simulation Studies

Shivali Malhotra on behalf of GEM Detector Simulation group

GEM Workshop, Sep 30 - Oct 4, 2019

GE1/1 Operation





Extensive study initiated by Alice and RD51 communities (Technical University of Munich, University of Zagreb et al.)

J. A. Merlin On behalf of the CMS Muon Group

Heat Transfer Study

3-D Model of a single hole GEM foil with 2500 °C inside hole



Time dependent solution using COMSOL Multi physics

Variation of Temperature with Time

1.5

1.5

2



Temperature with Point Source



Made an initial condition of heat coming from a point source at 2500 °C but acc. to the simulation it shows only 550 °C.

Interstrip Capacitance (GE2/1)

- Build a FEM for two strips
- First using MATLAB and now COMSOL for multi-strips
- Compared results for M1 & M4 size strips with analytical calculations (CMS IN-2018/006)
- Extended 2-D model to 3-D with 2, 3 and 4 strips using COMSOL





Interstrip Capacitance

- Impossible to do meshing of whole GE1/1 readout board
- Tried to do scan for each eta sector but still required more computing power
- Decided to use only 128 strips model



GE1/1 RO Board



Interstrip Capacitance (GE1/1)

Calculated and experimentally measured values of Interstrip capacitance of GE1/1-X-S RO Board (from CMS IN-2018/006)

Eta Sector	1	2	3	4	5	6	7	8
Calc. Cap./cm (pF/cm)	0.624	0.598	0.585	0.571	0.555	0.545	0.529	0.515
Avg. Meas. (pF/cm)	1.02	0.946	0.942	1.01	1.04	1.00	0.909	0.952
Meas. Error (pF/cm)	± 0.08	± 0.084	± 0.086	± 0.10	± 0.16	± 0.11	± 0.128	± 0.187
Ratio (Calc./Avg. Meas.)	0.61	0.63	0.62	0.57	0.54	0.54	0.58	0.54





Interstrip Capacitance (GE2/1)

M1 module with a 5um Cu layer 1 mm above the strips



Interstrip Capacitance (GE2/1)

Table 4: GE2/1 ROB Interstrip Capacitance With and Without Grounding Plate

Sect	or Module	Parameters	Avg. Meas. Ca w/o plate (pF	ap. Avg. Meas. Cap ⁽⁷⁾ w/plate (pF)	$(C_w/C_{w/o})$
1	M4	Original TDR design (Strip Gap: 0.2 mm)	21.69±0.05	25.85±0.27	1.192 ± 0.013
2	M4	Gap: 0.3 mm	19.98 ± 0.12	20.98 ± 0.03	1.050 ± 0.006
3	M4	2×Width, 0.5×Length	15.33 ± 0.03	20.16 ± 0.04	1.315 ± 0.004
4	M4	Long traces	27.87 ± 0.06	28.43 ± 0.07	1.020 ± 0.003
5	M1	Original TDR design (Strip Gap: 0.2 mm)	16.27 ± 0.04	19.04 ± 0.21	1.170 ± 0.013
6	M1	Gap: 0.3 mm	14.65 ± 0.07	18.26 ± 0.06	1.246 ± 0.007
7	M1	Gap: 0.4 mm	13.17 ± 0.04	14.85 ± 0.08	1.128 ± 0.007
8	M1	2×Width, 0.5×Length	11.82 ± 0.06	15.82 ± 0.32	1.338 ± 0.028
9	M1	0.5×Length	9.32±0.05	9.17±0.10	0.984 ± 0.012
10	M1	Original TDR Design, Long traces	20.58 ± 0.06	26.80 ± 0.14	1.302 ± 0.008
11	M1	Original TDR Design, Minimal traces	14.02 ± 0.02	14.82 ± 0.03	1.057 ± 0.003
10	M1	Original TDP Design Minimal traces 0.5xL anoth 2xW	He 10.20 0.07	10.00 0.11	0.004 1.0.012
12	INI I	Original TDK Design, Minimal traces, 0.5×Length, 2×W	idth 10.39±0.07	10.33±0.11	0.994±0.013
	Module	Parameters	Cap. w/o plate (pF)	Cap. with plate (pF)	C
	Module M4	Parameters Strip Gap: 0.2mm	Cap. w/o plate (pF) 16.119	Cap. with plate (pF) 16.252	0.994±0.013 C 1.008
	Module M4 M4	Original TDR Design, Minimal traces, 0.5×Lengui, 2× with Parameters Strip Gap: 0.2mm 2 x Width, 0.5 x Length	Cap. w/o plate (pF) 16.119 12.635	Cap. with plate (pF) 16.252 12.691	0.994±0.013 C 1.008 1.004
	Module M4 M4 M1	Original TDK Design, Minimal traces, 0.5×Length, 2× with the sign, 2× w	Cap. w/o plate (pF) 16.119 12.635 13.159	IO.33±0.11 Cap. with plate (pF) I6.252 I2.691 I3.607	0.994±0.013 C 1.008 1.004 1.034
	MI Module M4 M4 M1 M1	Parameters Strip Gap: 0.2mm 2 x Width, 0.5 x Length Strip Gap: 0.2mm 0.5 x Length	Idin 10.39±0.07 Cap. w/o plate (pF) 16.119 12.635 13.159 7.0076	IO.33±0.11 Cap. with plate (pF) I6.252 I2.691 I3.607 7.1788	0.994±0.013 C 1.008 1.004 1.034 1.024

Working with other parameters

Hole size Variation

- Single and triple GEM with both single mask & double mask configuration
- Simulate & estimate the variation in gain due to different hole size
- Obtained different hole geometry from digital and optical microscopy from Jeremie







Hole size Variation

13

CMS Internal Note

The content of this note is intended for CMS internal use and distribution only

01 October 2019

Simulation study of triple GEM detectors due to hole asymmetry on foils

Othmane Bouhali, Shivali Malhotra

Final list of authors will be fixed later

The Gas Electron Multiplier (GEM) is an amplification stage that has been introduce problem of discharges observed in gaseous detectors. There are two major the GEM foils: double mask and single mask. Despite being an effective is observed between the top and bottom diameters of GEM hole mask. In this paper we conduct an extensive simulationbased detectors. To characterize the properties of the performed with Garfield++ simulation packand the meshing needed for the field also compared with an experim





Deformation of Foil due to Stretching

I4

- Build a Finite Element Model (FEM) for a small area GEM foil (done in SolidWorks)
- Estimate the deformation on the holes due to force applied in x & y directions
- Extrapolate the results to large area GEM foil



Stretching force applied on 1mm x 1mm



FEM was built for GE1/1 chambers

Dead Area Simulation

- Base element created in ANSYS
 Extended simulation area to 4mm x 4mm
- Dead Area: -0.124 to -0.104; -0.02 to 0; 0.084 to 0.104 and 0.188 to 0.2





Summary

- For GE1/1 Operation we are performing the simulation to understand the dissipation of heat from a discharge.
- Trying to debug the issue generated with a point source.
- Simulated values of Interstrip Capacitance are in good agreement with the measured values for both GE1/1 & GE2/1.
- Note has been submitted related to the study of gain TOBE variation due to asymmetry in hole size.
- Other ongoing simulation studies have been reported